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To: WorldClassPatentQuality

Subject: Comments on Patent Quality

Patent Quality is difficult to measure. Any quick and easy means to measure quality of a patent will not actually be a measure of the patent's quality, but simply just a measurement of the number of references, rejections, office actions, RCE's, etc.

These numbers will only ensure standards across how different applications are treated. They will not go to the merits of the rejections, the novelty claimed, etc.

To truly measure quality of patents, each patent would need to go through a subsequent review. This would require the USPTO to divert resources and time, but would ultimately get at the goal, ensuring that issued patents represent novel and non-obvious inventions, and that non-novel and obvious applications get abandoned.

Putting in place metrics that encourage rejections will simply generate more rejections and increase the costs of inventors to get patent protection without ensuring that the right applications end up with patents.

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